



6

P/2699-26

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Toshikazu KITAJIMA et al.

Date : August 27, 2003

Serial No. : 10/624,871

Group Art Unit : ---

Filed : July 21, 2003

Examiner : ---

For : FILM THICKNESS MEASURING METHOD, RELATIVE DIELECTRIC
CONSTANT MEASURING METHOD, FILM THICKNESS MEASURING
APPARATUS, AND RELATIVE DIELECTRIC CONSTANT
MEASURING APPARATUS

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience
of the Examiner.

EXPRESS MAIL CERTIFICATE

I hereby certify that this correspondence is being
deposited with the United States Postal Service as
Express Mail Post Office to Addressee (mail label
#EV342531422US) in an envelope addressed to:
Commissioner for Patents, P.O. Box 1450, Alex-
andria, VA 22313-1450, on August 27, 2003:

Cheryl Desvignes

Name of Person Mailing Correspondence

Signature

August 27, 2003

Date of Signature

JAF:lac

Respectfully submitted,

James A. Finder

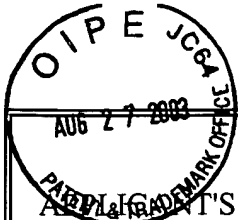
Registration No.: 30,173

OSTROLENK, FABER, GERB & SOFFEN, LLP

1180 Avenue of the Americas

New York, New York 10036-8403

Telephone: (212) 382-0700



APPLICANT'S ART CITATION (Use several sheets if necessary)	Application 10/624,871	OFGS File No. P/2699-26
	Applicant Toshikazu KITAJIMA et al.	
	Filing Date July 21, 2003	Group Art Unit --

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-5,475,319	12-1995	Hirae et al.	324	765	
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	6-349920	12-1994	Japan (corresponds to U.S. Patent No. 5,475,319 listed above)				X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Date Considered
----------	-----------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.